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(12) **United States Design Patent** (10) **Patent No.:** **US D791,660 S**
Arceo et al. (45) **Date of Patent:** **** Jul. 11, 2017**

(54) **INSTRUMENT CLUSTER**

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(**) Term: **15 Years**

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(51) **LOC (10) Cl.** **12-16**

(52) **U.S. Cl.**
USPC **D12/192**

(58) **Field of Classification Search**
USPC D12/192, 114, 195, 415; D10/102;
D15/17, 28
CPC G01D 11/28; G01D 11/30; G01D 11/24;
B60K 37/02; B60K 2350/2008
See application file for complete search history.

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Primary Examiner — Phillip S Hyder

(57) **CLAIM**

The ornamental design for an instrument cluster, as shown and described.

DESCRIPTION

FIG. 1 is a perspective view illustrating the instrument cluster.

FIG. 2 is front view of the instrument cluster.

FIG. 3 is a rear view of the instrument cluster.

FIG. 4 is a right view of the instrument cluster.

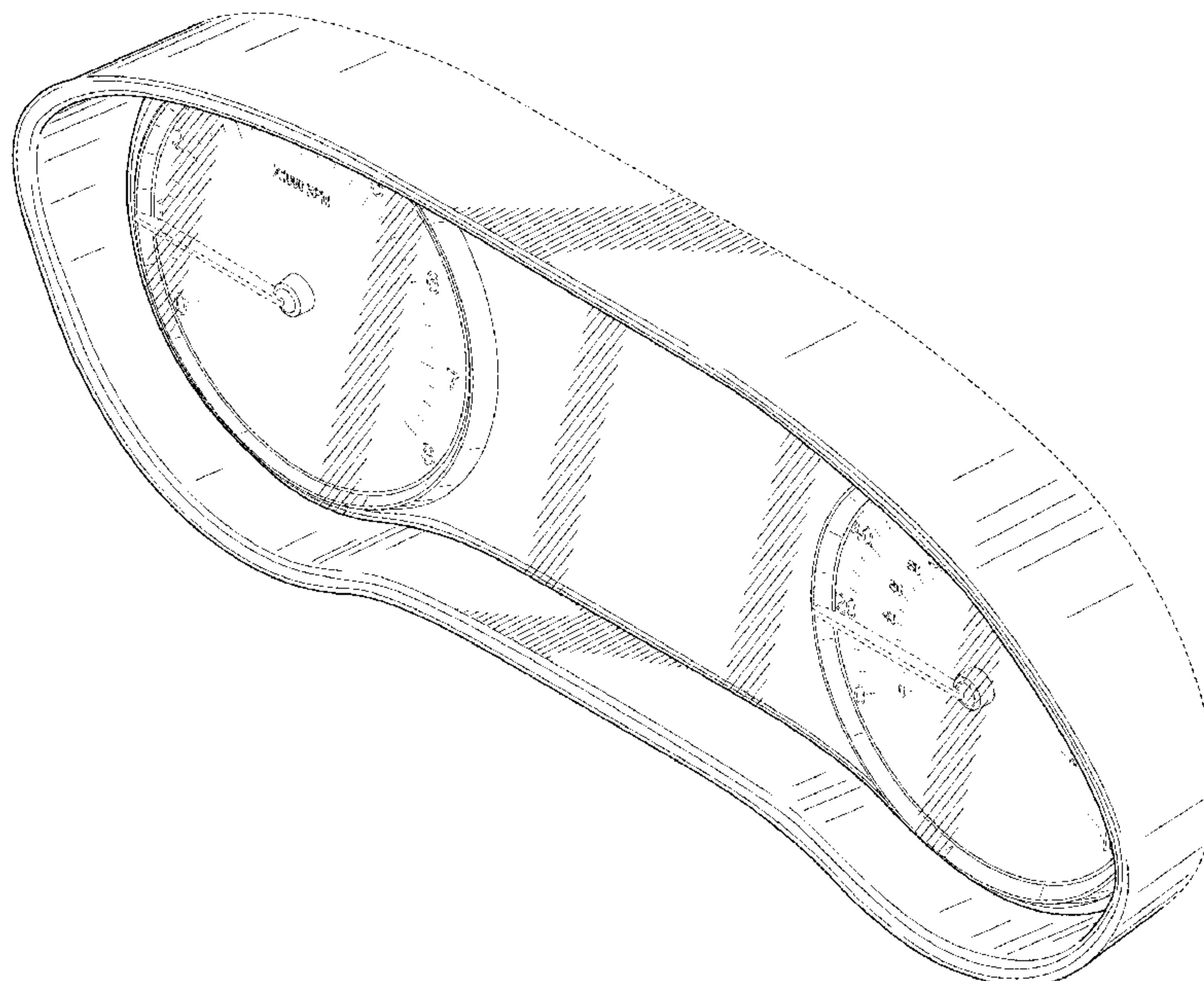
FIG. 5 is a left view of the instrument cluster. The rear edge of the instrument cluster is depicted by a broken line since it forms no part of the claimed design. Portions of the gauges are depicted by broken lines since they form no part of the claimed design;

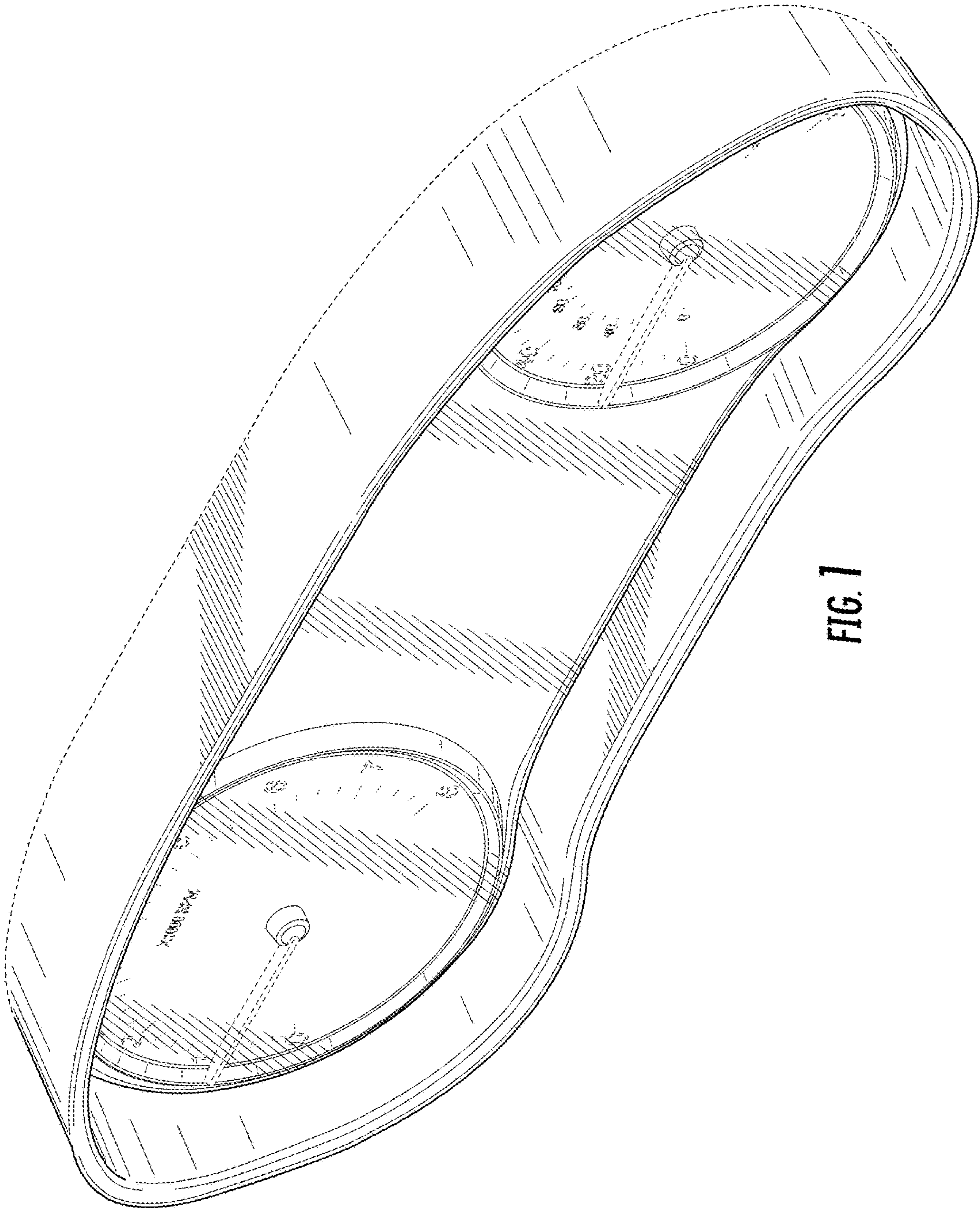
FIG. 6 is a top view of the instrument cluster; and,

FIG. 7 is a bottom view of the instrument cluster.

The rear edge of the instrument cluster is depicted by a broken lines since it forms no part of the claimed design. Portions of the gauges are depicted by broken lines since they form no part of the claimed design.

1 Claim, 5 Drawing Sheets





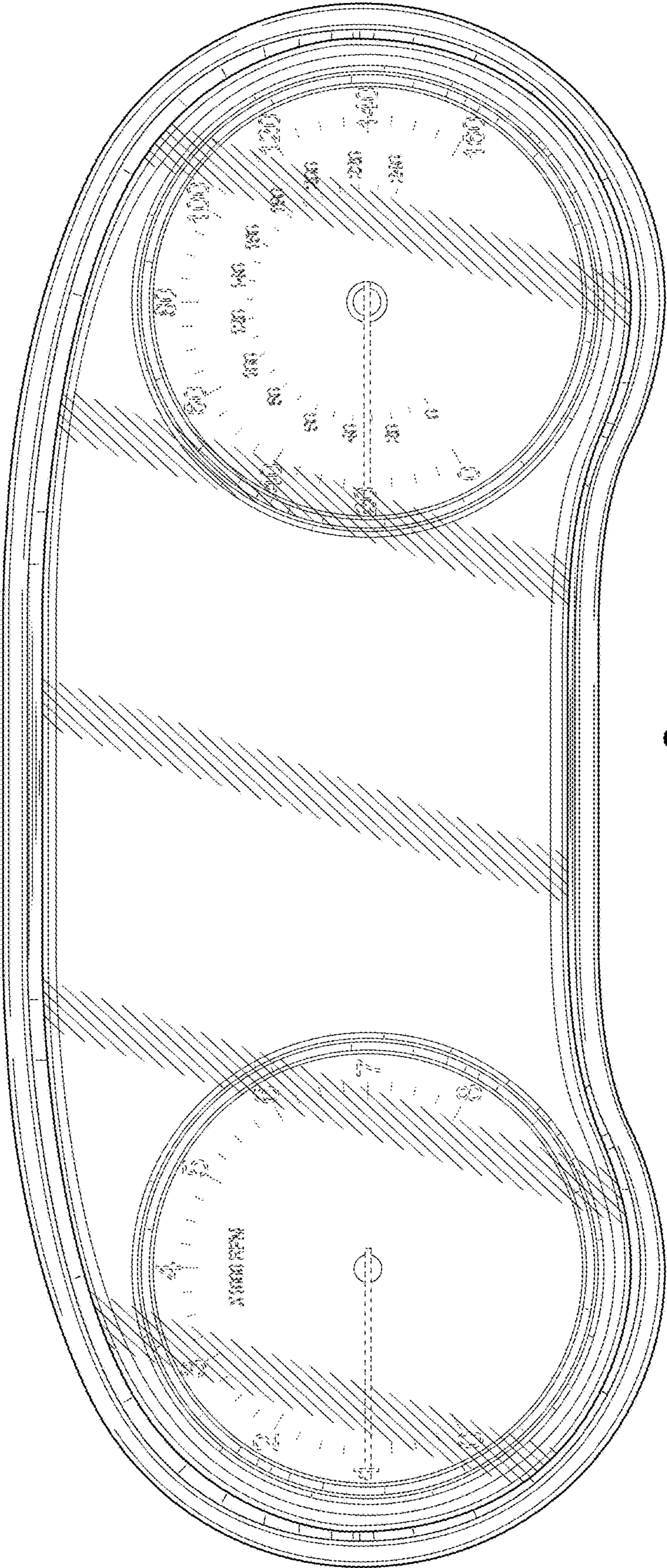


FIG. 2

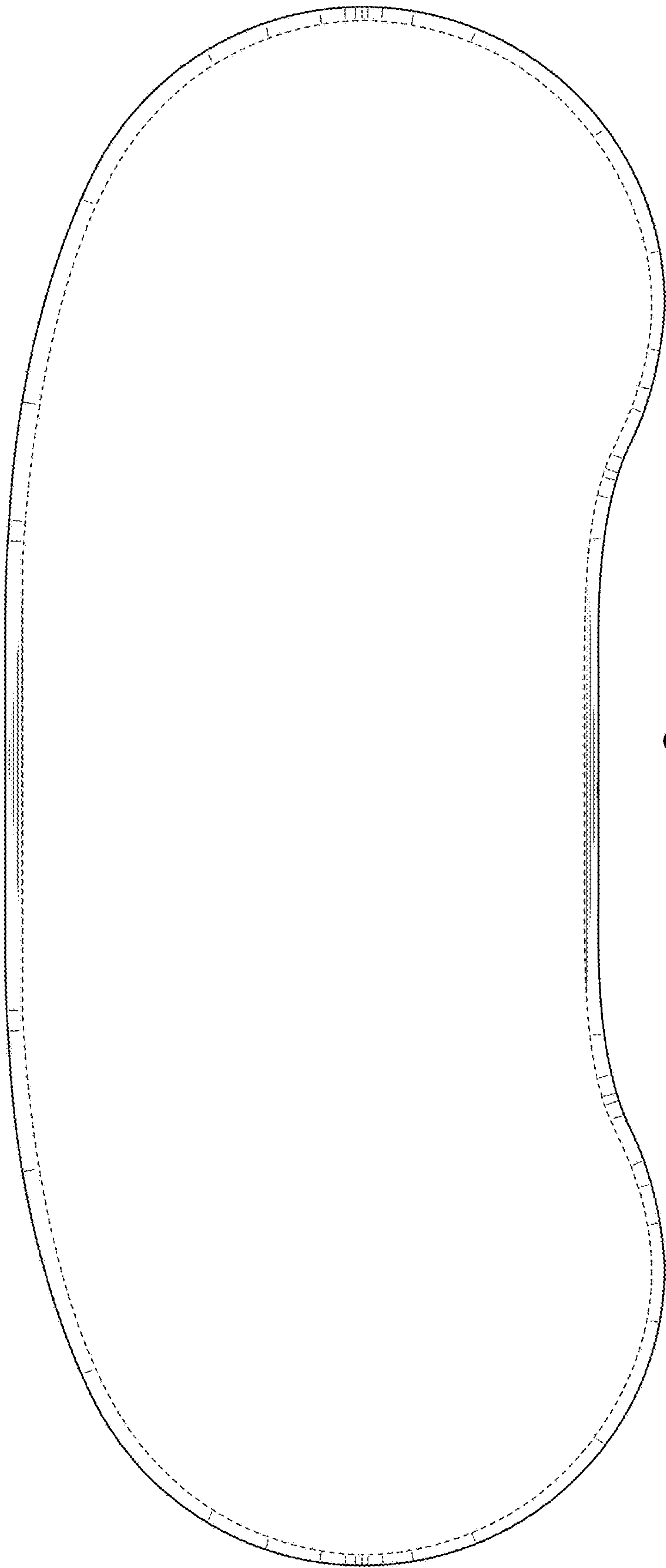


FIG. 3

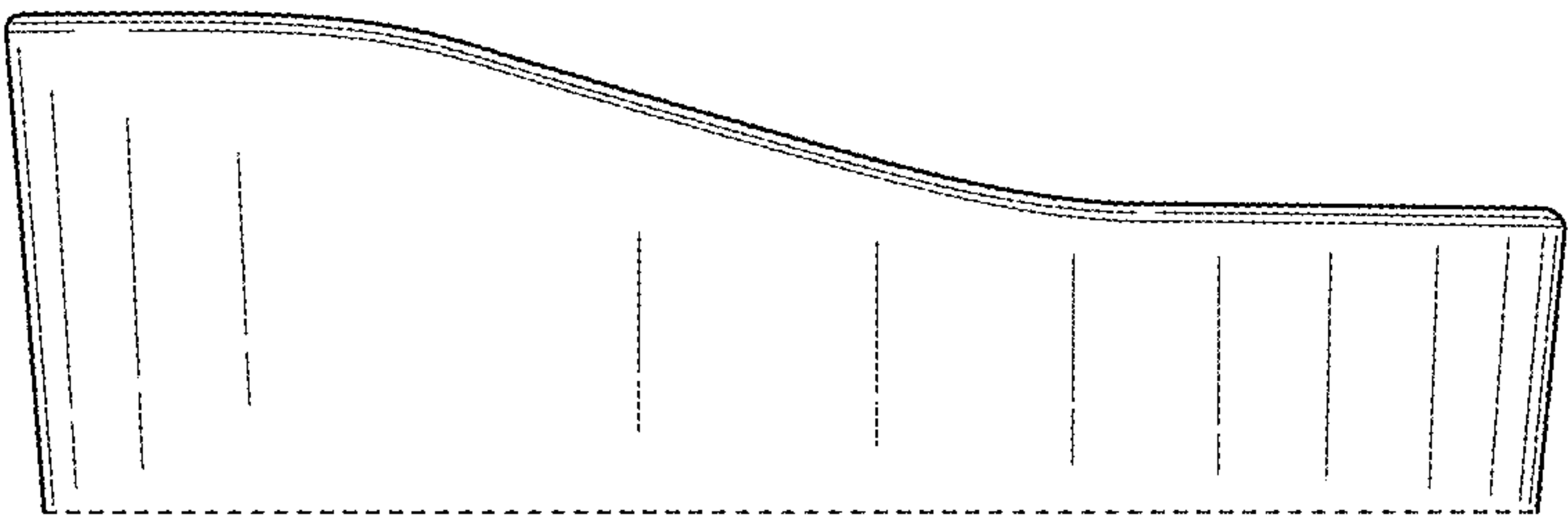


FIG. 5

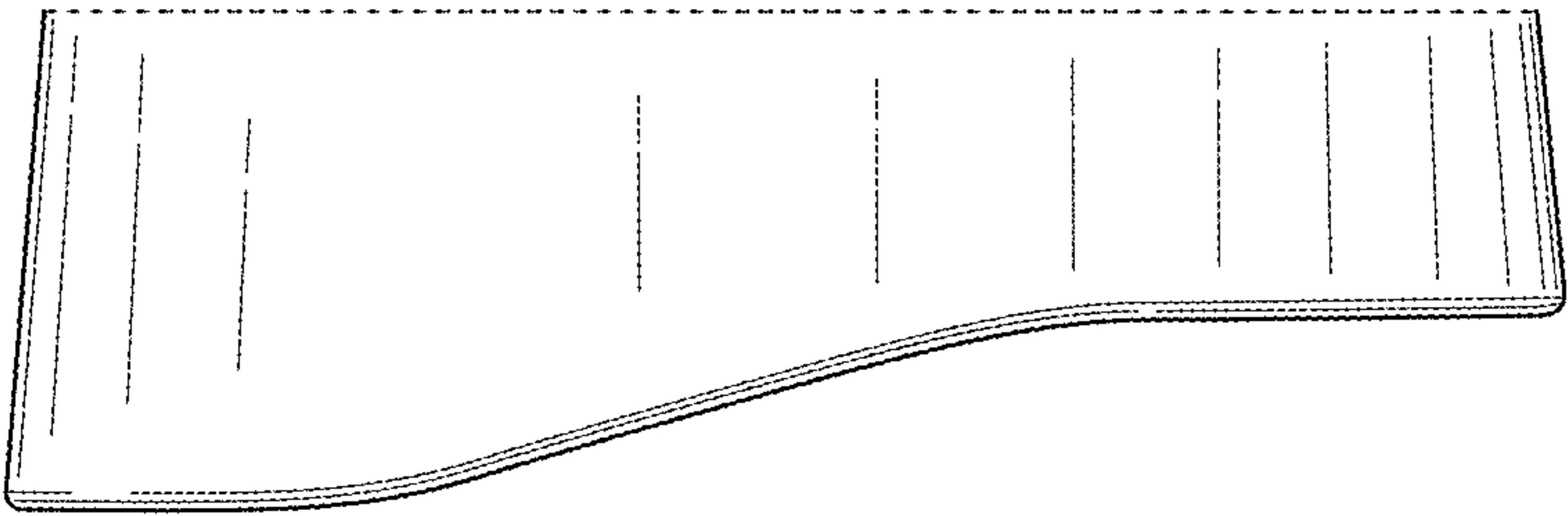


FIG. 4

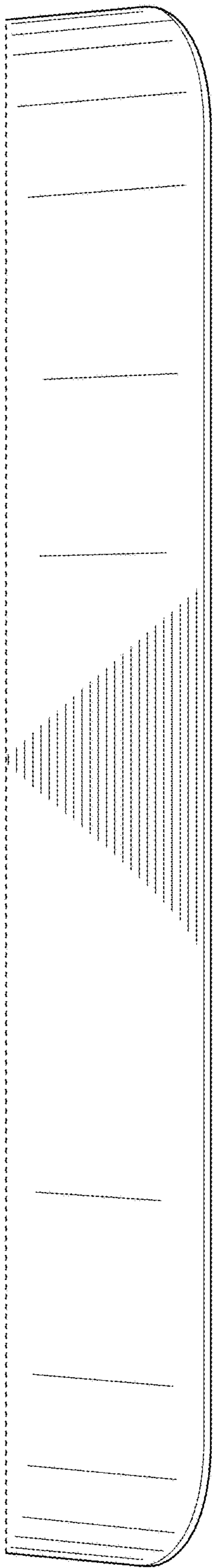


FIG. 6

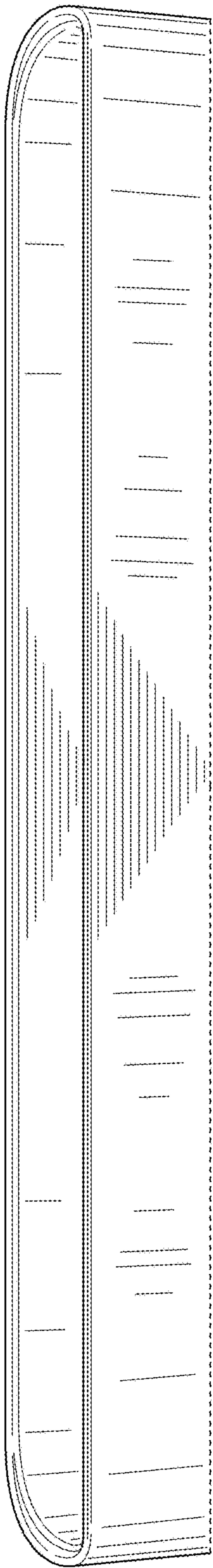


FIG. 7